

**AMENDMENTS TO THE CLAIMS**

1-20. (Canceled)

21. (Currently amended) A light detecting system comprising:

an imager device, comprising:

a substrate having a plurality of photosensitive regions; and

a substantially planar microlens array providing for a substantially planar imager device, said substantially planar microlens array formed over said plurality of photosensitive regions; said microlens array comprising;

a first light conductor having a plurality of concave recesses, and

a second light conductor within each recess and over substantially planar surfaces formed between said concave recesses of said first light conductor,

~~said microlens array being formed over said photosensitive regions without a light-shielding layer between said microlens array and said photosensitive regions.~~

22-26 (Canceled)

27. (Currently amended) An integrated circuit comprising:

an imager device, comprising:

a substrate having a plurality of photosensitive regions; a microlens array formed over said plurality of photosensitive regions; said microlens array providing for a substantially planar imager device comprising;

a first light conductor having a plurality of concave recesses, and

a second light conductor within each recess and over said first light conductor, said second light conductor being coextensive with an adjacent second light conductor in at least a first plane and having a substantially planar surface, and

readout circuitry coupled to said plurality of photosensitive regions, ~~said microlens array being formed over said photosensitive regions without a light-shielding layer between said microlens array and said photosensitive regions.~~

28-46. (Canceled)

47. (Previously presented) The light detecting system of claim 21, wherein said first light conductor has a first index of refraction and said second light conductor has a second index of refraction that is different from said first index of refraction.

48. (Previously presented) The light detecting system of claim 47, wherein said first index of refraction is less than said second index of refraction.

49. (Previously presented) The light detecting system of claim 21, wherein at least one of said first and second light conductors is formed of material selected from the group consisting of glass, an optical thermoplastic material, a polyimide, a thermoset resin, a photosensitive gelatin, and a radiation curable resin.

50. (Previously presented) The light detecting system of claim 21, further comprising a color filter formed over said second light conductor.

51. (Previously presented) The light detecting system of claim 21, further comprising a color filter formed below said first light conductor.

52. (Previously presented) The light detecting system of claim 21, wherein a portion of said second light conductor over said planar surface of said first light conductor has a thickness approximately equal to  $\lambda/2 * N$ , wherein  $\lambda$  refers to a particular wavelength of light

entering said microlens, and  $N$  refers to an index of refraction associated with said second light conductor.

53. (Previously presented) The integrated circuit of claim 27, wherein said first light conductor has a first index of refraction and said second light conductor has a second index of refraction that is different from said first index of refraction.

54. (Previously presented) The integrated circuit of claim 53, wherein said first index of refraction is less than said second index of refraction.

55. (Previously presented) The integrated circuit of claim 27, wherein at least one of said first and second light conductors is formed of material selected from the group consisting of glass, an optical thermoplastic material, a polyimide, a thermoset resin, a photosensitive gelatin, and a radiation curable resin.